## Notice of References Cited Application/Control No. 10/521,943 Examiner David J. Makiya Applicant(s)/Patent Under Reexamination SUEHIRO ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0245201 A1	11-2006	Wada et al.	362/545
*	В	US-7,246,921 B2	07-2007	Jacobson et al.	362/294
*	С	US-2007/0279910 A1	12-2007	Lin, Feng-Li	362/298
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.